

Notice of References Cited	Application/Control No. 10/757,829	Applicant(s)/Patent Under Reexamination SHIRAISHI ET AL.	
	Examiner Tai Van Nguyen	Art Unit 3729	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,579,658	04-1986	Moller, Klaus	210/483
	C	US-4,588,443	05-1986	Bache, Hans H.	106/644
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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